

35/705



Class	Subclass	ISSUE CLASSIFICATION



PATENT NUMBER

U.S. UTILITY Patent Application

1321 SCANNED	O.T.P.E. 580	PATENT DATE AA
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APPLICATION NO. 09/825027	CONT/PRIOR	CLASS 324	SUBCLASS 257	ART UNIT 2859	EXAMINER Robert
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APPLICANTS
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2829

TITLE
Clocked based method and devices for measuring voltage-variable capacitances and other on-chip parameters

ISSUING CLASSIFICATION							
ORIGINAL				CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
INTERNATIONAL CLASSIFICATION							

☐ Continued on Issue Slip Inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER <input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed. <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____ <input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	DRAWINGS Sheets Drwg. Figs. Drwg. Print Fig.			CLAIMS ALLOWED Total Claims Print Claim for O.G.	
	(Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
	(Primary Examiner) (Date)			ISSUE FEE Amount Due Date Paid	
	(Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER	

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